

Notice of References Cited	Application/Control No. 10/052,815		Applicant(s)/Patent Under Reexamination WIMMER ET AL.	
	Examiner Marianne L. Padgett		Art Unit 1762	Page 1 of 1

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NON-PATENT DOCUMENTS

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	V	Douglas Krajnovich, "Year-Threshold Photoablation Characteristics of Polyimide and Poly (Ethylene Terephthalate)", J. Applied Physics, Volume 82, #1, July 1, 1997, pages 427-435			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.